

WaferWave Technologies | Product Specification

100mm Monitor Grade Silicon Wafer (CZ, P-Type, <100>)

Product Overview:

This high-performance Monitor Grade substrate is sourced from **SEMI-certified European facilities** and is optimized for process monitoring, tool seasoning, and thin-film characterization. Featuring an exceptional Total Thickness Variation (TTV) of <10 µm and ultra-low particle counts, this wafer provides "near-prime" mechanical performance at a cost-effective price point for 2026 manufacturing standards.

1. Physical & Crystallographic Properties

Specification	Value
Diameter	100 ± 0.3 mm
Material	Silicon (Si)
Growth Method	Czochralski (CZ)
Grade	Test / Monitor Grade
Type / Dopant	P-Type / Boron (P/B)
Crystal Orientation	<100> ± 0.5°
Resistivity	> 1 Ω·cm

2. Mechanical Specifications

Specification	Value
Thickness	$525 \pm 25 \mu\text{m}$
Total Thickness Variation (TTV)	< 10 μm
Bow	< 30 μm
Warp	< 30 μm
Orientation Features	2 SEMI-Standard Flats

3. Surface & Purity Control

Specification	Value
Surface Finish (Front)	Mirror Polished (SSP)
Surface Finish (Back)	Etched / Standard Finish
Particle Count	< 10 ea/wf (@ $\geq 0.5 \mu\text{m}$)

4. Packaging & Documentation

Specification	Value
Packaging	25-Slot Polypropylene Cassette (Standard Wafer Jar)

Origin

European Union (Germany)

Compliance

Full Certificate of Analysis (COA) /
Conformance (COC) included

Contact Information:

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